Test Generation and Coverage

ICSE 2013 Tutorial

Automated Testing of GUI Applications Models, Tools and Controlling Flakiness



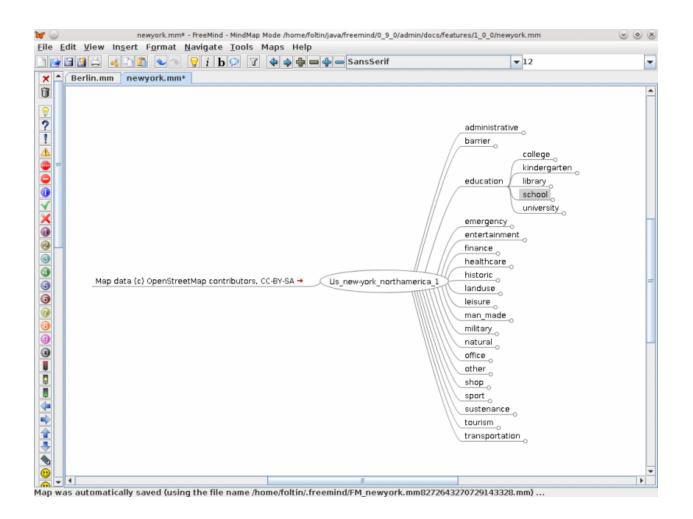






Lets return to our fault example from the beginning...

A Concrete Example



Setup:

In the Freemind Application there are four events: e_1 , e_2 , e_3 , e_4 , that correspond to {SetNodeToCloud, NewChildNode, NewParentNode, Undo}

A Fault:

Execution of either $\langle e_1, e_2, e_3 \rangle$ or $\langle e_2, e_1, e_3 \rangle$ throws an ArrayIndexOutOfBounds exception

Context Matters:

The combination $\langle e_{2}, e_{3} \rangle$ triggers this failure, but it needs the context of a cloud node (e_{1}) .

If we test $\langle e_2, e_3, e_1 \rangle$ the fault is not detected

Consecutive Events:

While $\langle e_{1,}e_{2,}e_{3}\rangle$ triggers the fault, but inserting e_{4} (undo), at points in the sequence (e.g. $\langle e_{1,}e_{2,}e_{4,}e_{3}\rangle$ causes the failure to be missed

Position is Important:

If the sequence $\langle e_{1,}e_{2}\rangle$ appears at the start of the test case, we have no chance of detecting this fault However, if it appears later then a sequence such as $\langle ...e_{1},...,e_{2,..}\rangle$ may trigger it

Coverage of Event Graphs

- Different types of coverage have been defined to reduce the complexity of EIG and EFG relationships
 - Cover all edges of EIG (length 2 test cases)
 - Cover all k-paths in graph, k > 2
 - Randomly select longer paths in graph

Example (3 interacting events)

<Cut>

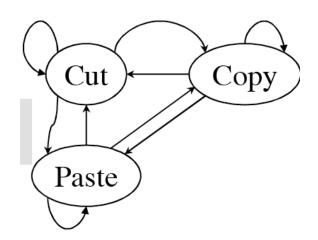
<Copy>

<Paste>

9 length 2 sequences

27 length 3 sequences

59,049 length 10 sequences



14 Million + length 15 sequences!

Possible Options

- Exhaustively generate all short paths:
 - length 2 (smoke tests)
 - or length 3
- Randomly generate longer paths
- Systematically sample paths

Shorter Sequences

Length 2 (Smoke Tests)

- 1.<*Cut, Cut>*
- 2.<*Cut, Copy>*
- 3.<Cut, Paste>
- *4.*<*Copy, Copy>*
- *5.*<*Copy, Paste>*
- *6.*<*Copy, Cut>*
- 7.<*Paste, Paste>*
- *8.*<*Paste, Cut>*
- *9.*<*Paste, Copy>*

Length 3-way

- *1.*<*Cut, Cut, Cut>*
- *2.*<*Cut, Cut, Copy*>
- 3.<Cut, Cut, Paste>
- *4.*<*Cut, Copy, Cut>*
- 5.<Cut, Copy, Paste>

•

.

.

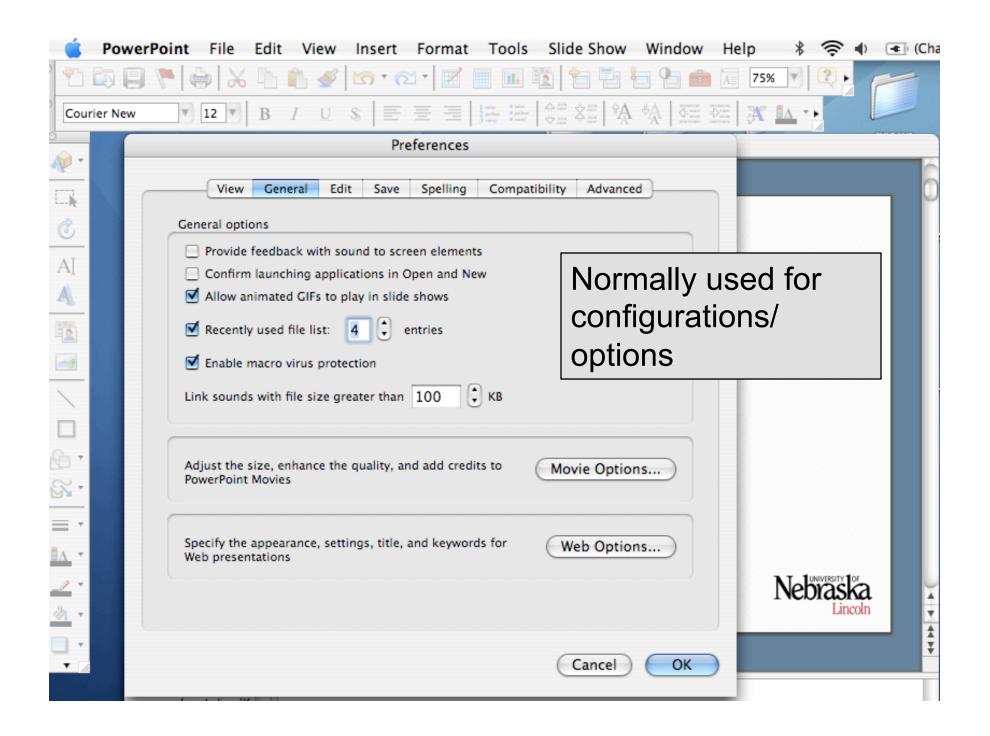
27.<Paste, Paste, Paste>

But!

- Research has shown that longer sequences find more faults
- The Freemind fault would go undetected with only length 2 sequences

Sampling Technique

- We can modify a technique from functional input testing:
 - Combinatorial interaction testing (CIT)
 - Covers all pairs or t-way combinations, but does not consider position
 - Used extensively to sample inputs, configurations, protocols
 - Tools exist to automatically generate samples



Combinatorial Testing (CIT)

	1	$\sqrt{\xi}$	3	4
1	Cut	Cut	Cut 🗸	Cut 🗸
2	Cut	Paste	Paste	Сору
3	Cut	Сору	Сору	Paste
4	Сору	Cut	Paste	Paste
5	Сору	Сору	Cut	Сору
6	Сору	Paste	Сору	Cut
7	Paste	Cut	Сору	Сору
8	Paste	Paste	Cut	Paste
9	Paste	Сору	Paste	Cut

Combine all pairs between locations (2-way)

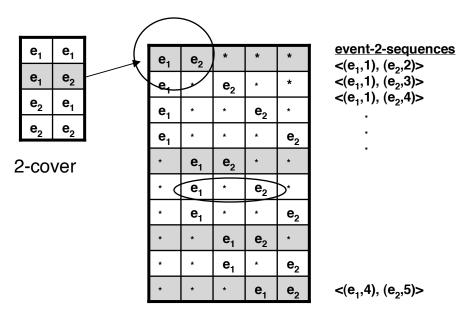
Combinatorial Testing (CIT)

1	Cut	Cut	Cut	Cut
2	Cut	Paste	Paste	Сору
3	Cut	Сору	Сору	Paste
4	Сору	Cut	Paste	Paste
5	Сору	Сору	Cut	Сору
6	Сору	Paste	Copy	Cut
7	Paste	Cut	Сору	Сору
8	Paste	Paste	Cut	Paste
9	Paste	Сору	Paste	Cut

Combinatorial Testing (CIT)

1	Cut	Cut	Cut	Cut
2	Cut	Paste	Paste	Сору
3	Cut	Сору	Сору	Paste
4	Сору	Cut	Paste	Paste
5	Сору	Сору	Cut	Сору
6	Сору	Paste	Сору	Cut
7	Paste	Cut	Сору	Сору
8	Paste	Paste	Cut	Paste
9	Paste	Сору	Paste	Cut
		3-way CIT	•••	
27				

Relaxed CIT Coverage



All possible event-2-sequences for event-2-tuple (e1,e2)

Three Length 5 Test Sequences

e ₁	e ₂	e ₁	e ₂	e ₂
e ₁	e ₁	e ₂	e ₁	e ₁
e ₂	e ₂	e ₂	e ₁	e ₂

Definitions

Definition

An event-t-tuple (e_i, e_j, \dots, e_t) is an ordered tuple of size t of events from E. A set of events E gives rise to $|E|^t$ event-t-tuples, i.e., all possible permutations of events.

To account for context, we need to associate positions within a sequence to specific events.

Definition

An event-position in a length-k sequence S is an ordered pair (e, p), where event $e \in E$ is at position p $(1 \le p \le k)$.

Definitions

Definition

An event-t-sequence is a vector of event-positions of length t, $<(e_i,p_1),(e_j,p_2),...,(e_n,p_t)>$, where $k\geq t$, $1\leq p_x\leq k$ for all x, $1\leq x\leq t$, $p_1< p_2<...< p_t$, and $e_i,e_j,...e_n\in E$.

Definition

An event-consecutive-t-sequence is an event-t-sequence $<(e_i,p_1),(e_j,p_2),...,(e_k,p_t)>$ such that $p_x=p_{x-1}+1$, for all $1 < x \le t$.

Definition

An event-non-consecutive-t-sequence is an event-t-sequence $<(e_i,p_1),(e_j,p_2),...(e_n,p_t)>$, where $p_1< p_2<...< p_t$, such that at least one interval $(p_2-p_1),...,(p_t-p_{t-1})$ is greater than 1.

Coverage Adequacy

Definition

A test suite is t-cover adequate if it executes all possible event-t-tuples in the form of an event-consecutive-t-sequence at least once.

Definition

A test suite is t^+ -cover adequate if it executes all possible event-t-tuples in the form of an event-non-consecutive-t-sequence at least once. Adequacy is zero when t=k.

Coverage Adequacy

Definition

A test suite is t^* -cover adequate if it is both t-cover adequate and t^+ - cover adequate for a common set of events E.

Definition

A test suite with test cases of length k is t-k-covering array adequate when t < k and it contains all possible event-t-sequences at least once.

Example

Three events:

{ClearCanvas, DrawCircle, Refresh}

Example

t-Cover						
ClearCanvas ClearCanvas Refresh DrawCircle						
DrawCircle	Refresh	ClearCanvas	Refresh			
Refesh	Refresh	DrawCircle	ClearCanvas			
ClearCanvas	DrawCircle	DrawCircle	Refresh			

```
Missing t^+-cover tuples: \{ClearCanvas, ClearCanvas\}, \{Refresh, Refresh\}
```

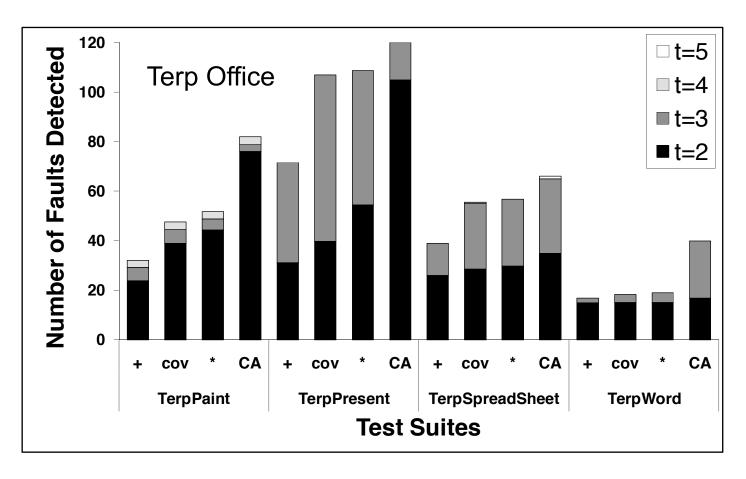
Example

t^+ -Cover						
ClearCanvas Refresh DrawCircle Refresh						
Refresh	ClearCanvas	DrawCircle	ClearCanvas			
DrawCircle	Refresh	ClearCanvas	Refresh			
DrawCircle	ClearCanvas	Refresh	DrawCircle			

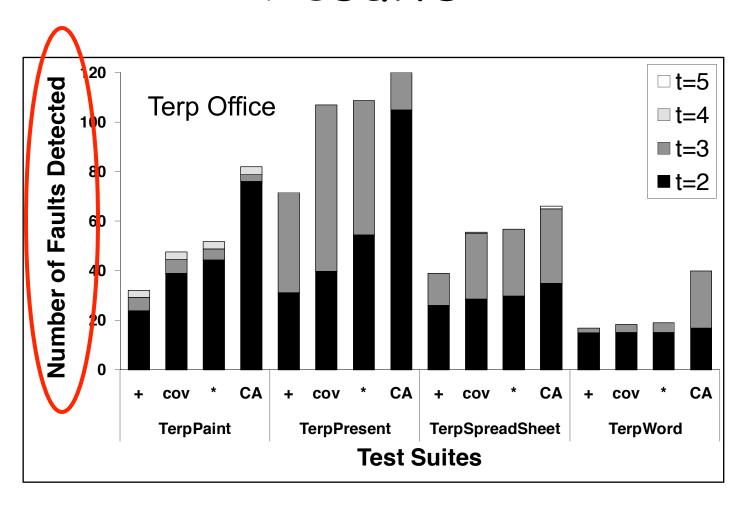
```
Missing t-cover tuples: \{ClearCanvas, ClearCanvas, ClearCanvas\}, \{DrawCircle, DrawCircle\}, \{Refresh, Refresh\}
```

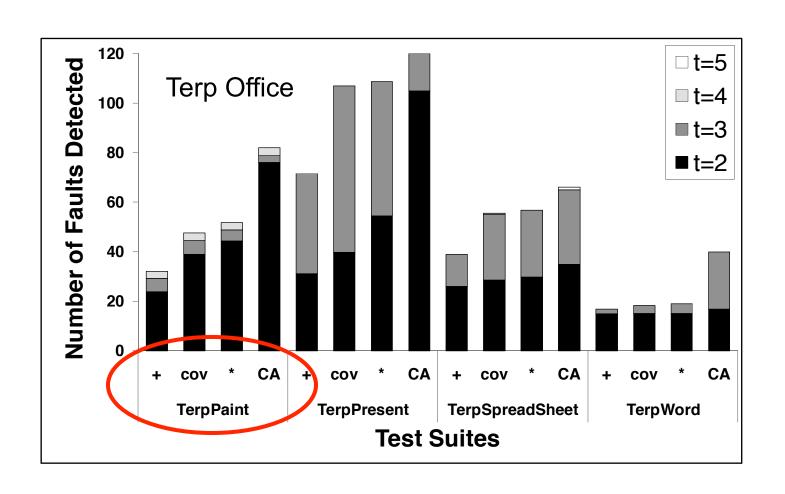
Study Overview

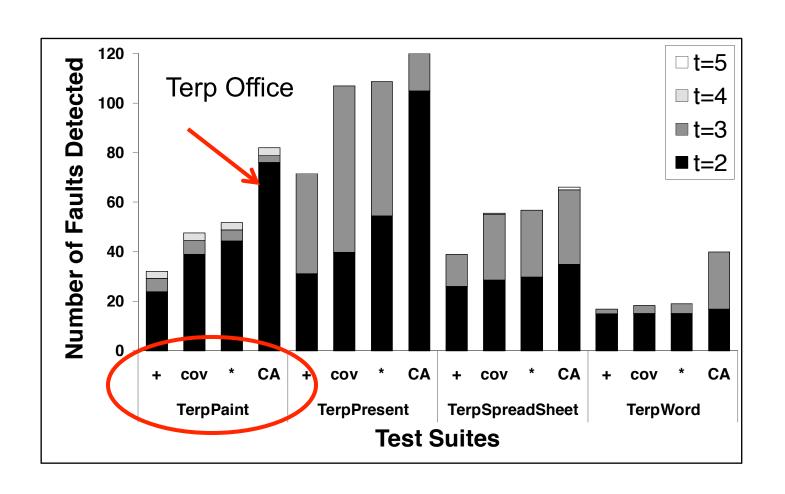
- Conducted an empirical study on 4 TerpOffice Applications¹ and 4 Open Source Applications²
- Generated all 2,3,4,5 CIT samples of length 10 (until TS size > 20,000)
- TerpOffice seeded faults
- Open Source detected crashes
- All faults undetected by 2-way sequences
- Compared size and fault detection at each strength
- 1. University of Maryland
- 2. SourceForge

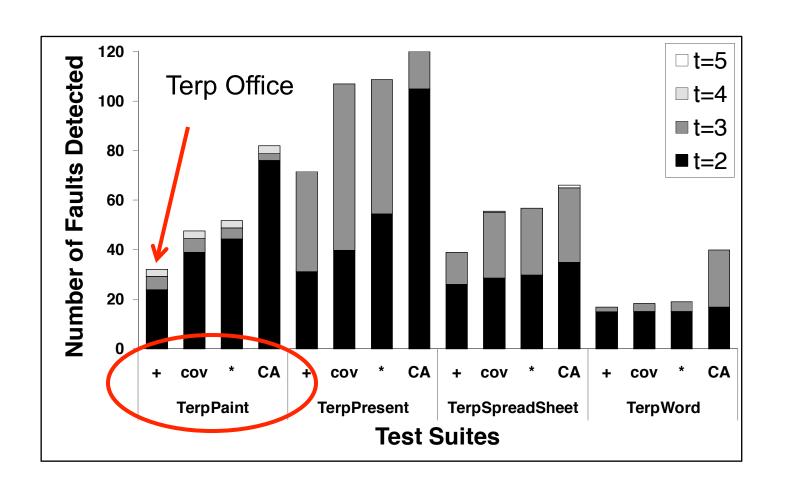


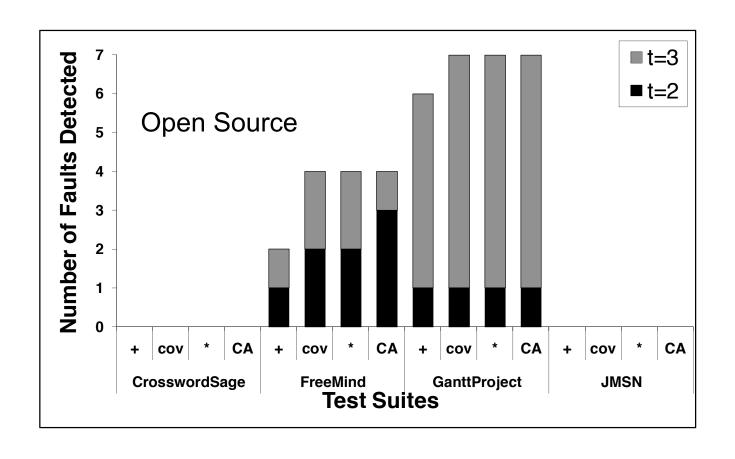
[Yuan et al.TSE 11]











Cost Trade-off

 The criteria with fewer test cases find fewer faults

Group	Strength	t^+ -cover	t- $cover$	t^* - $cover$	t-10-CA		
	TerpPaint						
Group 1	t=2	19.0/43.8	33.0/123.4	38.0/161.8	69/1055		
Group 2	t=2	3.4/73.6	4.0/208.6	4.0/273.4	4/1783		
Group 3	t=2	1.4/8.8	2.4/22.6	2.8/28.8	5/171		
Group 3	t=3	6.8/40.2	8.0/255.8	8.0/291.8	8/2870		
Group 5	t=4	5.0/22.0	5.0/81.4	5.0/84.2	5/3428		
T							
Δ.							

Avg. # Faults detected

Avg. Size of Test Suite

Cost Trade-off

 The criteria with fewer test cases find fewer faults

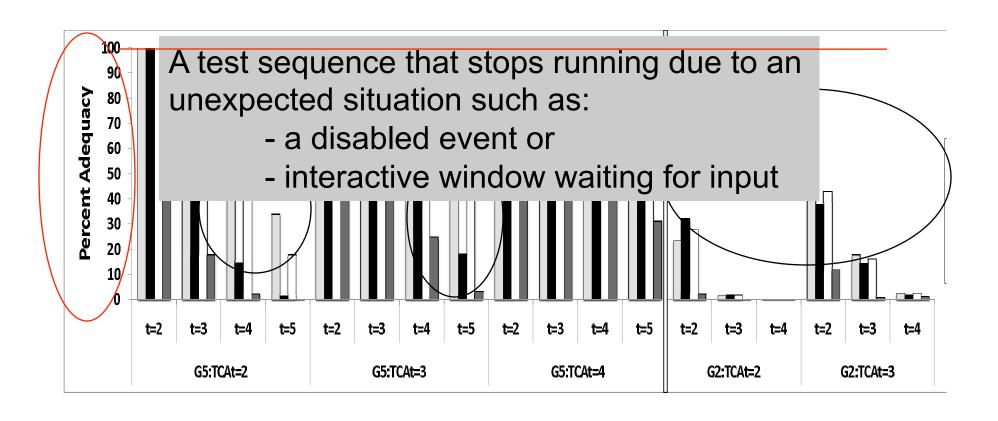
Group	Strength	t^+ -cover	t- $cover$	t^* - $cover$	t-10-CA
Group 1	t=2	19.0/43.8	33.0/123.4	38.0/161.8	69/1055
Group 2	t=2 1	9 faults for	und: 44 tes	cases	4/1783
Group 3	t=2				5/171
Group 3	t=3	9 faults for	und: 1055 t	est cases	8/2870
Group 5	t=4	5.0/22.0	5.0/81.4	5.0/84.2	5/3428
T D .					
Avg. # Faults detected Avg. Size of Test Suite					

Cost Trade-off

 The criteria with fewer test cases find fewer faults

Group Strengt 3 faults found: 73 test cases				<i>t</i> -10-CA			
Group 1 $t=2$ 4 faults found: 1783 test cases				69/1055			
Group 2	t=2	3.4/73.6	4.0/208.6	4.0/273.4	4/1783		
Group 3	t=2	1.4/8.8	2.4/22.6	2.8/28.8	5/171		
Group 3	t=3	6.8/40.2	8.0/255.8	8.0/291.8	8/2870		
Group 5	t=4	5.0/22.0	5.0/81.4	5.0/84.2	5/3428		
T D '.							

Many Infeasible Test Sequences



Problem with Infeasible Sequences

- Causes test harness to hang
 - Entire test suite may not run
- Reduces CIT coverage
- May reduce fault detection ability
- Requires manual intervention

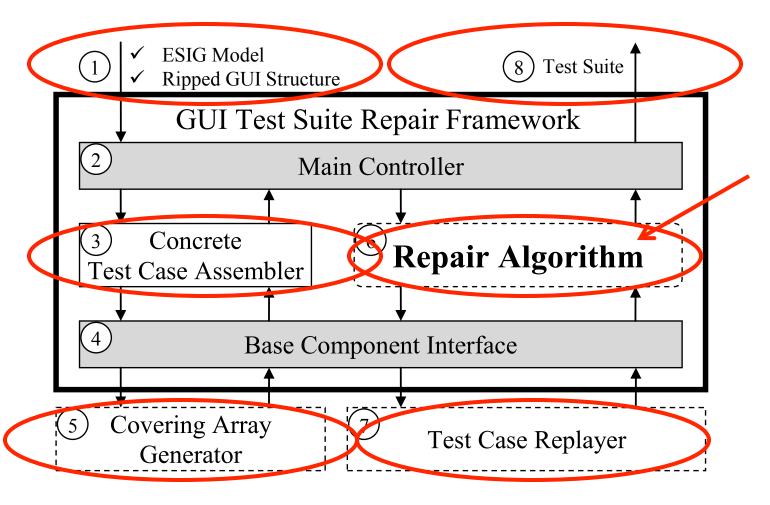
Can This be Avoided?

- Perfect state machine model could provide us with exact feasibility
 - Hard to create
 - But this won't scale which is why we use the stateless EFG/EIG

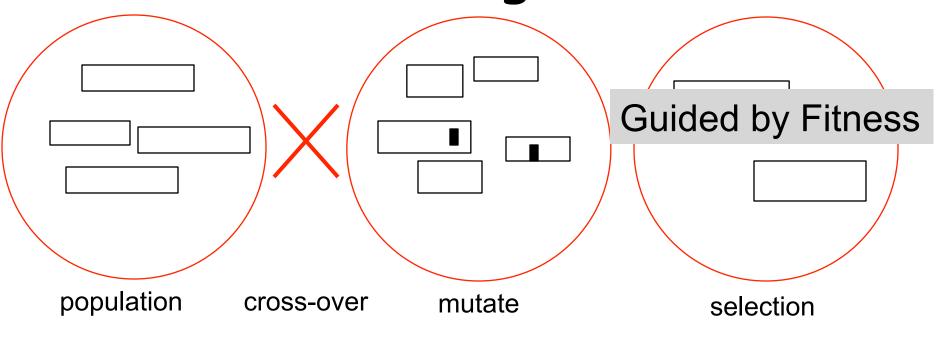
Handling Infeasibility

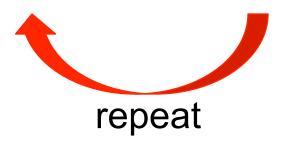
- Examined the problem of infeasibility in generating longer sequences
- Developed a framework to automatically repair test suites
- Uses a genetic algorithm to iteratively increase coverage while avoiding infeasible sequences

Repair Framework



Genetic Algorithm





Fitness

Combines coverage and feasibility

$$fitness(s) = b * cov_s + p(l - f_s)$$

- cov_s= newly covered t-sets in test case
- ! = length of test case
- f_s = point of failure
- p and b are constants
 - 100,000 and 10 in our implementation

Case Study

- Seven synthetic subjects
 - Helps with determinism
 - Can isolate types of infeasible patterns
 - Do not need to worry about faults/other causes of infeasibility
- Programs and artifacts available on COMET

Case Study

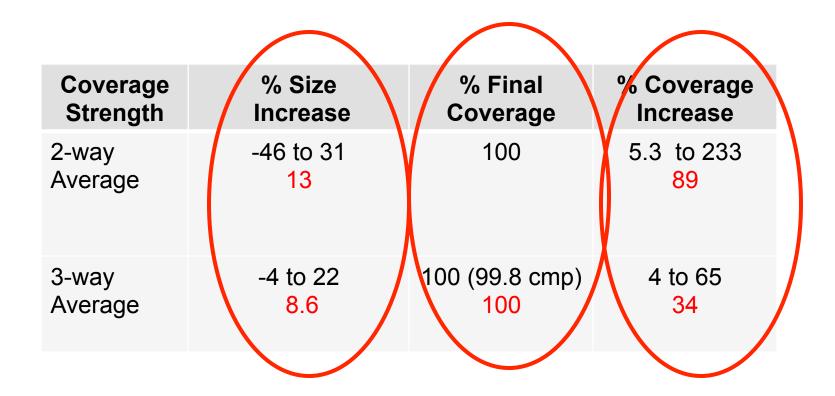
- 7 Subjects with 3 to 5 events
 - Disabled, Requires, Event Consecutive (2 and 3-way), Excludes (2 and 3-way), Compound





- Metrics:
 - Coverage of test suites after repair
 - Size of repaired test suites
 - Time to execute

Results(RQ1): Effectiveness



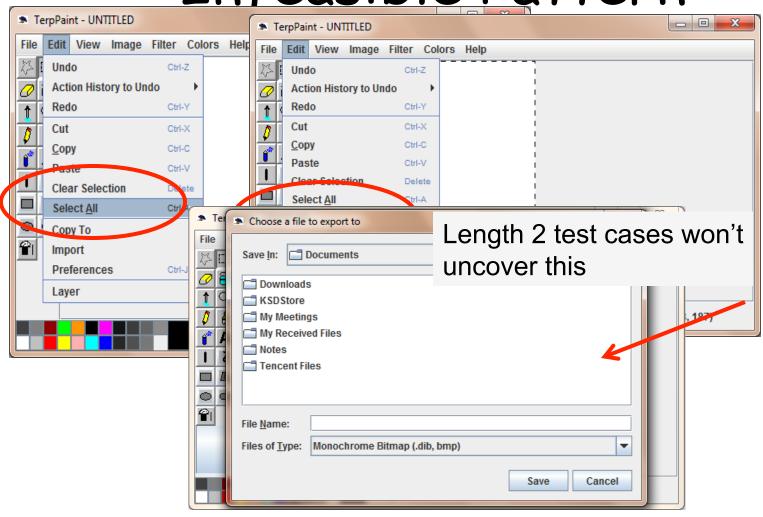
Results(RQ2): vs. Random

Coverage Strength	Avg. Random % Coverage	Avg. GA % Coverage	
2-way Length 5 Length10	95 (80-100) 85 (70-99)	100	
3-way Length 5 Length 10	92 (80-99) 90 (74-99)	100 100	

Applying to Real Programs

- Length 10 test suite for TerpPaint used in fault detection study
- Well understood program
 - long test sequences did not achieve 100% coverage
- Our GA achieved 100 percent coverage except:
 - <Select All, Copy To>

A 2-way Consecutive Infeasible Pattern



Summary

- We have shown some basic test generation techniques that utilize the EFG/EIGs
- We have presented several types of coverage criteria that have cost/ effectiveness tradeoffs
- We have discussed the need for test suite repair in this scenario

References

- 1. X. Yuan, M.B. Cohen and A.M. Memon, Covering array sampling of input event sequences for automated GUI testing, *Proceedings of the IEEE International Conference on Automated Software Engineering (ASE)* (short paper), Atlanta, GA, November 2007, pp. 405-408.
- 2. X. Yuan, M.B. Cohen and A.M. Memon, GUI Interaction Testing: Incorporating Event Context, *IEEE Transactions on Software Engineering*, 37(4), 2011, pp. 559-574.
- 3. S. Huang, M.B. Cohen and A.M. Memon, Repairing GUI Test Suites Using a Genetic Algorithm, *International Conference on Software Testing, Verification and Validation (ICST)*, April 2010, pp. 245-254.

This material is based upon work supported by the National Science Foundation under Grant No. <u>CNS-0855139</u> and <u>CNS-0855055</u>. <u>CNS-1205472</u> and <u>CNS-1205501</u>.

Any opinions, findings, and conclusions or recommendations expressed in this material are those of the author(s) and do not necessarily reflect the views of the National Science Foundation.

ICSE 2013 Tutorial

Automated Testing of GUI Applications Models, Tools and Controlling Flakiness







Atif M. Memon and Myra B. Cohen